## RFM15N12, RFM15N15, RFP15N12, RFP15N15

File Number 1443

DIT-39-11

# **N-Channel Enhancement-Mode Power Field-Effect Transistors**

15 A, 120 V - 150 V

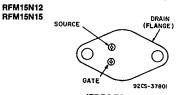
r<sub>DS</sub>(on): 0.15 Ω

### Features:

- SOA is power-dissipation limited
- Nanosecond switching speeds
   Linear transfer characteristics
- High input impedance
- Majority carrier device

3875081 0018173 7

01E 18173

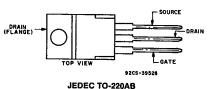


JEDEC TO-204AA

RFP15N12 RFP15N15

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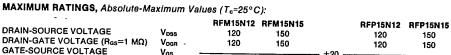
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The RFM15N12 and RFM15N15 and the RFP15N12 and RFP15N15\* are n-channel enhancement-mode silicon-gate power field-effect transistors designed for applications such as switching regulators, switching converters, motor drivers, relay drivers, and drivers for high-power bipolar switching transistors requiring high speed and low gate-drive power. These types can be operated directly from integrated circuits.

The RFM-types are supplied in the JEDEC TO-204AA steel package and the RFP-types in the JEDEC TO-220AB plastic package.

\*The RFM and RFP series were formerly RCA developmental numbers TA9195 and TA9230, respectively.



	DRAIN-SOURCE VOLTAGE	Voss	120	150		120	150	v
	DRAIN-GATE VOLTAGE (R <sub>gs</sub> =1 MΩ)	VDGR -	120	150				•
•	GATE-SOURCE VOLTAGE		120	100		120	150	v
		Vas			±20			— V
	DRAIN CURRENT RMS Continuous	l <sub>D</sub>			15			
	Pulsed					_		- A
		юм			40			— A
	POWER DISSIPATION							
	@ Tc=25°C	PT	100	100				
	0.0	• •		· - +		75	75	w
	Derate above Tc=25°C		0.80	0.80		0.6	0.6	W/°C
	OPERATING AND STORAGE						•.•	0
	TEMPERATURE	<b>+ -</b>						
	TENTERATORE	Tj, Tstg			<ul> <li>-55 to +150</li> </ul>	)		°C

#### 116.

N-Channel Enhancement Mode

TERMINAL DESIGNATIONS

3875081 G E SOLID STATE

01E 18174 D

1.25

1.67

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**RFM15N15** 

RFP15N12,

RFP15N15

1.25

1.67

°C/W

Standard Power MOSFETs

#### RFM15N12, RFM15N15, RFP15N12, RFP15N15 ELECTRICAL CHARACTERISTICS At Case Temperature ( $T_c$ ) = 25°C unless otherwise specified T-39-11LIMITS 7-3.9-13 **RFM15N12** RFM15N15 TEST RFP15N12 **RFP15N15** CHARACTERISTICS SYMBOL CONDITIONS UNITS MIN. MAX MIN. MAX. $I_{\rm D}=1~{\rm mA}$ Drain-Source Breakdown Voltage BV<sub>DSS</sub> 120 -----150 ۷ $V_{GS}=0$ $V_{GS} = V_{DS}$ Gate Threshold Voltage 2 4 2 4 ۷ VGS(th) $I_D = 1 \text{ mA}$ $V_{\text{ds}}=100~V$ 1 \_ $V_{\text{DS}} = 120 \text{ V}$ 1 \_ -----Zero Gate Voltage Drain Current loss $T_{C}=125^{\circ}C$ μA $V_{\text{DS}} = 100 \text{ V}$ \_ 50 ----- $V_{DS} \doteq 120 \ V$ 50 \_ $V_{GS}=\pm~20~V$ Gate-Source Leakage Current lass \_ 100 \_ 100 nΑ $V_{\text{DS}}=0$ I<sub>D</sub> = 7.5 A \_\_\_\_ 1.125 1.125 \_ $V_{\text{GS}}=10~\text{V}$ Drain-Source On Voltage V<sub>DS</sub>(on)\* ۷ $I_{D} = 15 \text{ A}$ 3 3 \_ \_ $V_{GS} = 10 \ V$ Static Drain-Source On Resistance · I<sub>D</sub> = 7.5 A ros(on)\* 0.15 0.15 Ω \_ $V_{GS} = 10 V$ $V_{DS} = 10 V$ Forward Transconductance g<sub>fa</sub>ª 5 5 mho $I_D = 7.5 \ A$ Input Capacitance Ciss $V_{DS} = 25 V$ 1700 1700 — \_ **Output Capacitance** Coss $V_{GS} = 0 V$ 750 750 ρF f = 1MHz **Reverse Transfer Capacitance** Crss 350 350 Turn-On Delay Time V<sub>DD</sub>=75 V t₀(on) 50(typ.) 75 50(typ.) 75 150(typ.) Rise Time $I_D = 7.5 \text{ A}$ 150(typ.) 225 225 t, ns Turn-Off Delay Time 185(typ.) t₄(off) $R_{gen}=R_{gs}=50~\Omega$ 185(typ.) 280 280 Fall Time tr $V_{GS}=10 \ V$ 125(typ.) 190 125(typ.) 190 RFM15N12,

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\*Pulsed: Pulse duration = 300 µs max., duty cycle = 2%.

**Thermal Resistance** 

Junction-to-Case

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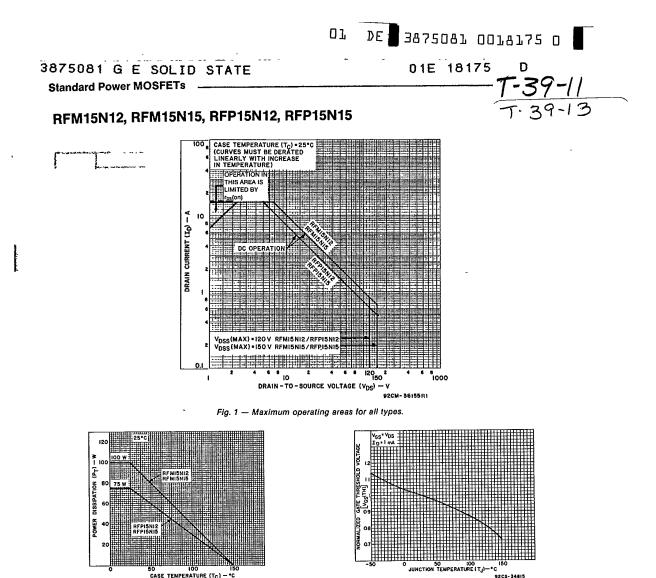
### SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

			LIMITS				
CHARACTERISTIC	SYMBOL	TEST CONDITIONS	RFM15N12 RFP15N12		RFM15N15 RFP15N15		UNITS
			MIN.	MAX.	MIN.	MAX.	]
Diode Forward Voltage	VsD	I <sub>SD</sub> =7.5 A	1	1.4		1.4	V
Reverse Recovery Time	trr	I <sub>F</sub> =4 A d <sub>IF</sub> /dt=100 A/μs	200(typ)		200(typ)		ns

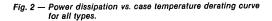
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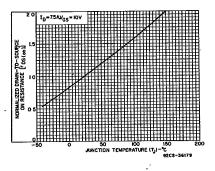
\*Pulse Test: Width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%.

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50 100 .... CASE TEMPERATURE (T<sub>C</sub>) - \*C 92CS-36154





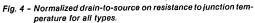
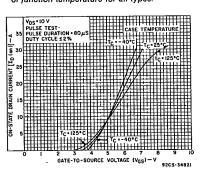
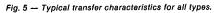


Fig. 3 — Typical normalized gate threshold voltage as a function of junction temperature for all types.



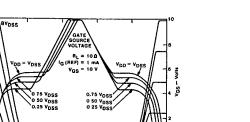


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80 1G (REF) IG (ACT)

9205-17656

Fig. 6 - Normalized switching waveforms for constant gate-current drive.

DRAIN S

TIME -

20 1<sub>G</sub> (REF) 1<sub>G</sub> (ACT) CE VOLTAG

150

112 #HoA

VDS -

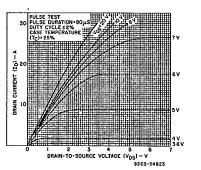


Fig. 7 — Typical saturation characteristics for all types.

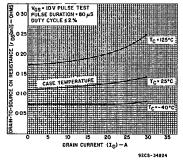


Fig. 8 - Typical drain-to-source on resistance as a function of drain current for all types.

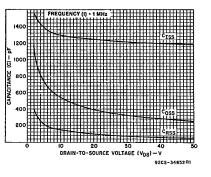
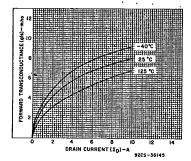
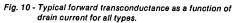


Fig. 9 — Capacitance as a function of drain-to-source voltage for all types.





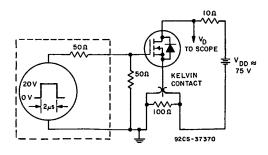


Fig. 11 - Switching Time Test Circuit

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